

Search Notes

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Examiner

Eric B. Chen

Applicant(s)/Patent under
Reexamination

LEE, HEON

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search (PALM) (UPDATED)	11/22/2005	EC
EAST (all databates) (UPDATED) - see search history printout	11/22/2005	EC
216/18,22,38,39,46,47;438/3,257,710, 723,724,725,692,696; 438/745,756, 757; 216/104,107,109 (text search only)	11/22/2005	EC